


<b>Search Notes</b>  	<b>Application/Control No.</b>  09766130	<b>Applicant(s)/Patent Under Reexamination</b>  LIPTON ET AL.
	<b>Examiner</b>  Nguyen, Jennifer T	<b>Art Unit</b>  2629

SEARCHED			
Class	Subclass	Date	Examiner
345	7-9,30,87,94-96	10/11/08	jn

SEARCH NOTES		
Search Notes	Date	Examiner
US-PAT, US-PGPUB, JPO, EPO, DERWENT, IEEE, inventors, claim interferences	10/11/08	jn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
359	196,618,462	10/11/08	jn
349	15	10/11/08	jn
348	57	10/11/08	jn

/J. T. N./  
Examiner, Art Unit 2629